Search Notes				

Application/Control No	. Applicant(s)/Patent under Reexamination
10/671,441	BYUN, YOUNG-KWANG
Examiner	Art Unit
Randall Chin	1744

SEARCHED				
Class	Subclass	Date	Examiner	
15	143.1		İ	
15	167.1			
16	111.1			
D4	107			
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INTERFERENCE SEARCHED				
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SEARCH NO (INCLUDING SEARCI	TES H STRATEGY)
	DATE	EXMR
Inventor name search	8/3/2005	RC
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